

## **Reliability Monitoring Results**

**Quarters:** Q1/2021 to Q4/2021 Based on structural similarity

Supplier User Part Number

Nexperia B.V. NXS0108BQ

Part Description: 8-bit Dual supply translating transceiver; open drain; auto direction sensing

Function Family: NXS Process family: Sub micron Package family: DHVQFN

JESD47		Test Conditions	Duration	# Lots	# Quantity	# Rejects
# 1	<b>TEST</b> Pre- and Post-Stress Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below
# 2	PC Preconditioning	JESD22-A113 MSL 1	N/A	314	19231	0
# 5a	HTOL EFR High Temperature Operating Life Extrinsic	JESD22-A108 $Tj = 150^{\circ}C$ $V_{CCMAX} \le V \le 1.2*V_{CCMAX}$	48 hours or 168 hours	122	29837	0
# 5b	<b>HTOL IFR</b> High Temperature Operating Life Intrinsic	JESD22-A108 Tj = 150°C $V_{CCMAX} \le V \le 1.2*V_{CCMAX}$	≥500 hours	70	5655	0
# 7	TC Temperature Cycling	JESD22-A104 -65 °C to 150°C	≥500 cycles	178	10253	0
# 9	uHAST / HAST unbiased or biased High Accelerated Stress Test	JESD22-A101 Tamb = 130 °C, RH = 85%, V = V <sub>CCMAX</sub>	96 hours	156	8978	0

## Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above) Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic(HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Produc Family		Quantity	Rejects	Extrinsic Failure Rate (PPM)	Intrinsic Failure Rate (FIT)	MTTF (hrs)
NXS	DHVQFN	5655	0	31	0.6	1.68 E+09